

Notice of References Cited	Application/Control No. 09/970,453	Applicant(s)/Patent Under Reexamination EYAL ET AL.	
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Sandia National Laboratories, MEM bibliography, BIOMEMS/mFluidics, pages 1-2, October 1998
	V	SAND 2001-3412P
	W	Khoo and Liu., 22 nd Annual EMBS, July 23-28, 2000. Chicago, IL, pages 2394-2397.
	X	Lessard et al., CAT.INIST., A scanning apertureless fluorescence microscope, 1999.

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Maluf, N., XP-0021517476, 2000, page 42, An Introduction to Microelectromechanical Systems Engineering, Artech House Publishers, Boston, London..
	V	
	W	
	X	

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